

Important notice

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Kind regards,

Team Nexperia

PHKD3NQ10T

Dual N-channel TrenchMOS standard level FET Rev. 02 — 16 December 2010 Pt

Product data sheet

Product profile 1.

1.1 General description

Dual standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics
- Suitable for use in compact designs due to low profile

1.3 Applications

DC-to-DC converters

Motor and relay drivers

1.4 Quick reference data

Table 1. **Quick reference data**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	100	V
I _D	drain current	T_{sp} = 25 °C; One MOSFET conducting	-	-	3	Α
P _{tot}	total power dissipation	$T_{sp} = 25 ^{\circ}C$	-	-	2	W
Static chara	acteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 1.5 \text{ A};$ $T_j = 25 \text{ °C}$	-	70	90	mΩ
Dynamic cl	naracteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 3 \text{ A};$ $V_{DS} = 80 \text{ V}; T_j = 25 \text{ °C}$	-	8	-	nC



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source1		D. D. D. D. D.
2	G1	gate1	8 <u> </u>	D1 D1 D2 D2
3	S2	source2		
4	G2	gate2		
5	D	drain2	1	
6	D	drain2	SOT96-1 (SO8)	S1 G1 S2 G2
7	D	drain1		mbk725
8	D	drain1		

3. Ordering information

Table 3. Ordering information

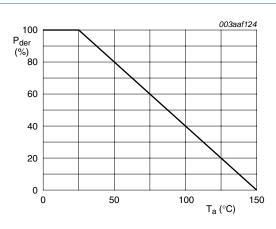
Type number	Package		
	Name	Description	Version
PHKD3NQ10T	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1

4. Limiting values

Table 4. Limiting values

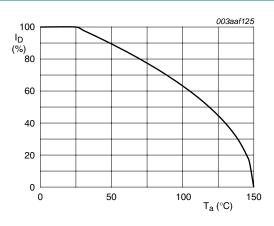
In accordance with the Absolute Maximum Rating System (IEC 60134).

$\begin{array}{c} V_{DS} & \text{drain-source voltage} \\ V_{DGR} & \text{drain-gate voltage} \\ V_{GS} & \text{gate-source voltage} \\ I_{D} & \text{drain current} \\ & \begin{array}{c} T_{j} \geq 25 \text{ °C; } T_{j} \geq 25 \text{ °C; } R_{GS} = 20 \text{ k}\Omega \\ & -20 & 20 & V \\ \hline T_{sp} = 25 \text{ °C; both MOSFETs conducting} \\ & -20 & 20 & V \\ \hline T_{sp} = 70 \text{ °C; one MOSFET conducting} \\ & -24 & A \\ \hline T_{sp} = 70 \text{ °C; both MOSFETs conducting} \\ & -24 & A \\ \hline T_{sp} = 70 \text{ °C; both MOSFETs conducting} \\ & -24 & A \\ \hline T_{sp} = 70 \text{ °C; both MOSFETs conducting} \\ & -24 & A \\ \hline T_{sp} = 25 \text{ °C; One MOSFET conducting} \\ & -24 & A \\ \hline T_{sp} = 25 \text{ °C; both MOSFETs conducting} \\ & -24 & A \\ \hline T_{sp} = 25 \text{ °C; both MOSFET conducting} \\ & -24 & A \\ \hline T_{sp} = 25 \text{ °C; both MOSFET conducting} \\ & -24 & A \\ \hline T_{sp} = 25 \text{ °C; both MOSFET conducting} \\ & -25 °C; both MOSFET cond$	Symbol	Parameter	Conditions	Min	Max	Unit
$V_{GS} \qquad \text{gate-source voltage} \qquad \qquad \begin{array}{c} -20 & 20 & V \\ I_D \\ I_$	V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	100	V
$I_{D} \qquad \text{drain current} \qquad \frac{T_{sp} = 25 \text{ °C; both MOSFETs conducting}}{T_{sp} = 70 \text{ °C; one MOSFET conducting}} \qquad - \qquad 2.2 \qquad \text{A} \\ \hline I_{Sp} = 70 \text{ °C; one MOSFET conducting}} \qquad - \qquad 2.4 \qquad \text{A} \\ \hline I_{Sp} = 70 \text{ °C; both MOSFETs conducting}} \qquad - \qquad 1.7 \qquad \text{A} \\ \hline I_{Sp} = 25 \text{ °C; One MOSFET conducting}} \qquad - \qquad 3 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad T_{Sp} = 25 \text{ °C; pulsed; One MOSFET}} \qquad - \qquad 12 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad \text{peak drain current}} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM} \qquad - \qquad 1.2 \qquad \text{A} \\ \hline I_{DM}$	V_{DGR}	drain-gate voltage	$T_j \le 150 \text{ °C}; T_j \ge 25 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	100	V
$T_{sp} = 70~^{\circ}\text{C}; \text{ one MOSFET conducting} \qquad - \qquad 2.4 \qquad \text{A}$ $T_{sp} = 70~^{\circ}\text{C}; \text{ both MOSFETs conducting} \qquad - \qquad 1.7 \qquad \text{A}$ $T_{sp} = 25~^{\circ}\text{C}; \text{ One MOSFET conducting} \qquad - \qquad 3 \qquad \text{A}$ $I_{DM} \qquad \text{peak drain current} \qquad T_{sp} = 25~^{\circ}\text{C}; \text{ pulsed}; \text{ One MOSFET} \qquad - \qquad 12 \qquad \text{A}$	V _{GS}	gate-source voltage		-20	20	V
$T_{sp} = 70 ^{\circ}\text{C; both MOSFETs conducting} \qquad - \qquad 1.7 \qquad \text{A}$ $T_{sp} = 25 ^{\circ}\text{C; One MOSFET conducting} \qquad - \qquad 3 \qquad \text{A}$ $I_{DM} \qquad \text{peak drain current} \qquad T_{sp} = 25 ^{\circ}\text{C; pulsed; One MOSFET} \qquad - \qquad 12 \text{A}$	I _D	drain current	T _{sp} = 25 °C; both MOSFETs conducting	-	2.2	Α
T_{sp} = 25 °C; One MOSFET conducting - 3 A T_{sp} = 25 °C; pulsed; One MOSFET - 12 A			T _{sp} = 70 °C; one MOSFET conducting	-	2.4	Α
I_{DM} peak drain current $T_{sp} = 25$ °C; pulsed; One MOSFET - 12 A			T _{sp} = 70 °C; both MOSFETs conducting	-	1.7	Α
·			T _{sp} = 25 °C; One MOSFET conducting	-	3	Α
Conducting	I _{DM}	peak drain current	T _{sp} = 25 °C; pulsed; One MOSFET conducting	-	12	Α
P_{tot} total power dissipation $T_{sp} = 70 ^{\circ}\text{C}$ - 1.3 W	P _{tot}	total power dissipation	T _{sp} = 70 °C	-	1.3	W
$T_{sp} = 25 ^{\circ}\text{C}$ - 2 W			T _{sp} = 25 °C	-	2	W
T _{stg} storage temperature -65 150 °C	T _{stg}	storage temperature		-65	150	°C
T _j junction temperature -65 150 °C	Tj	junction temperature		-65	150	°C
Source-drain diode	Source-drain o	diode				
I_S source current $I_{sp} = 25 ^{\circ}\text{C}$ - 2 A	Is	source current	T _{sp} = 25 °C	-	2	Α
I_{SM} peak source current T_{sp} = 25 °C; pulsed; $t_p \le 10 \text{ s}$ - 12 A	I _{SM}	peak source current	T_{sp} = 25 °C; pulsed; $t_p \le 10 \text{ s}$	-	12	Α



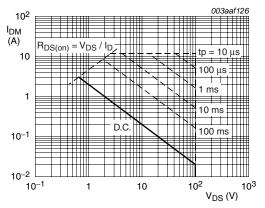
 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}\text{C})}} \times 100 \,\%$

Fig 1. Normalized total power dissipation as a function of mounting base temperature



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature



 T_{mb} = 25 °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	Surface mounted on FR4 board ; either or both MOSFETs conducting ; t ≤ 10 sec	-	-	62.5	K/W
		Surface mounted on FR4 board; either or both MOSFETs conducting	-	150	-	K/W

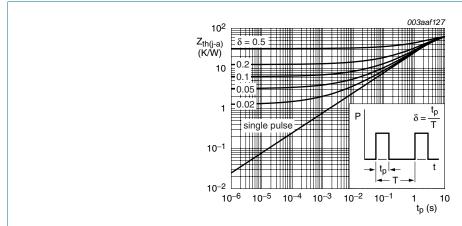


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source breakdown	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	89	-	-	V
	voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	100	-	-	V
$V_{GS(th)}$	gate-source threshold	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	6	V
	voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 150 \text{ °C}$	1.1	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	2	3	4	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μΑ
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
R _{DSon}	drain-source on-state	$V_{GS} = 10 \text{ V}; I_D = 1.5 \text{ A}; T_j = 150 \text{ °C}$	-	-	216	mΩ
	resistance	V _{GS} = 10 V; I _D = 1.5 A; T _j = 25 °C	-	70	90	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 3 \text{ A}; V_{DS} = 80 \text{ V}; V_{GS} = 10 \text{ V};$	-	21	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C	-	2.5	-	nC
Q_{GD}	gate-drain charge		-	8	-	nC
C _{iss}	input capacitance	$V_{DS} = 20 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	633	-	pF
Coss	output capacitance	T _j = 25 °C	-	103	-	pF
C _{rss}	reverse transfer capacitance		-	61	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 50 \text{ V}; R_L = 15 \Omega; V_{GS} = 10 \text{ V};$	-	6	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega; T_j = 25 °C$	-	12	-	ns
t _{d(off)}	turn-off delay time		-	20	-	ns
t _f	fall time		-	10	-	ns
L _D	internal drain inductance	measured from drain lead to centre of die ; T_j = 25 °C	-	2.5	-	nΗ
L _S	internal source inductance	measured from source lead to source bond pad; $T_j = 25$ °C	-	5	-	nΗ
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 2 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.8	1.2	V
t _{rr}	reverse recovery time	$I_S = 2 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s}; V_{GS} = 0 \text{ V};$	-	55	-	ns
Q _r	recovered charge	$V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$	-	135	-	nC

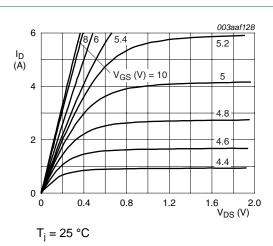


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

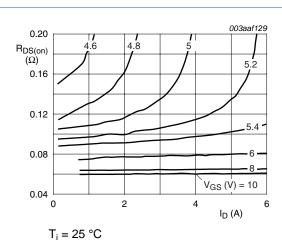


Fig 6. Drain-source on-state resistance as a function of drain current; typical values

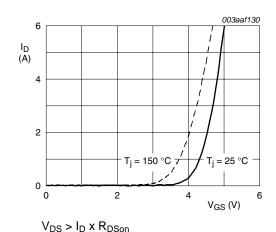


Fig 7. Transfer characteristics: drain current as a function of gate-source voltage; typical values

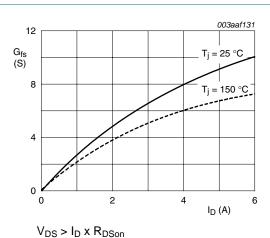


Fig 8. Forward transconductance as a function of drain current; typical values

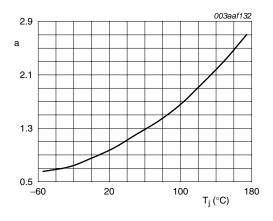


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature

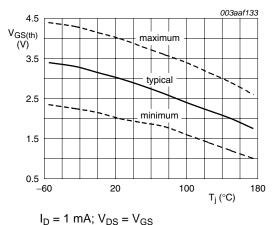


Fig 10. Gate-source threshold voltage as a function of junction temperature

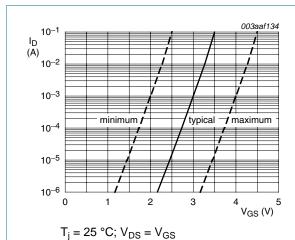
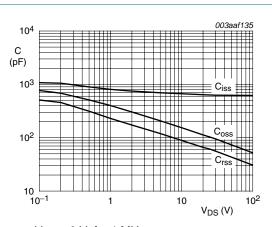


Fig 11. Sub-threshold drain current as a function of gate-source voltage



 $V_{GS} = 0 V$; f = 1 MHz

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

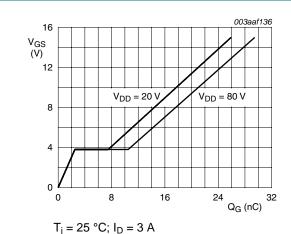
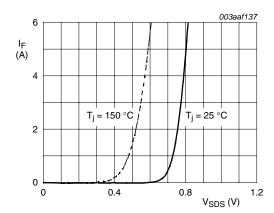


Fig 13. Gate-source voltage as a function of gate charge; typical values



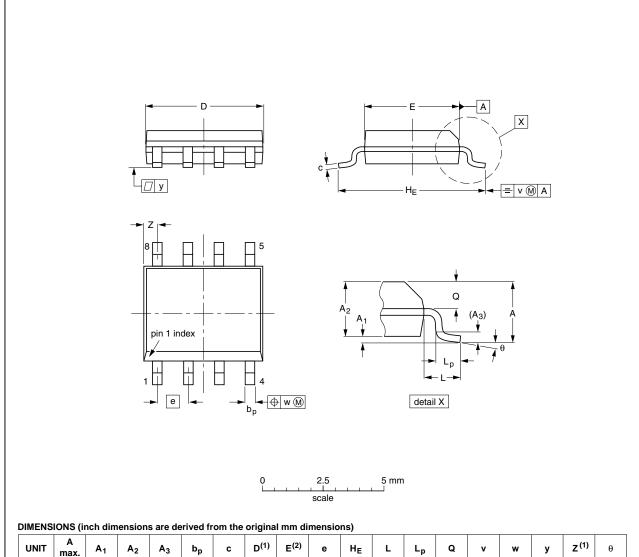
 $V_{GS} = 0 V$

Fig 14. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

7. Package outline

SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	σ	v	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	5.0 4.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.20 0.19	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.
- 2. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	DEC JEITA		PROJECTION	ISSUE DATE
SOT96-1	076E03	MS-012				99-12-27 03-02-18

Fig 15. Package outline SOT96-1 (SO8)

PHKD3NQ10T

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes				
PHKD3NQ10T v.2	20101216	Product data sheet	-	PHKD3NQ10T v.1				
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 							
	 Legal texts ha 	ve been adapted to the new	company name where	appropriate.				
PHKD3NQ10T v.1	19990801	Product specification	-	-				

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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10. Contact information

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Dual N-channel TrenchMOS standard level FET

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